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**Interior of Telecommunication Equipment-Measurement of
Electromagnetic Emissions-150kHz to 1GHz. Part 6:
Measurement of Conducted Emissions. Magnetic Probe Method**

电信设备内部电磁发射诊断技术要求和测量方法(150kHz~1GHz) 第6部分：传导
发射测量 磁场探头方法

(English Translation)

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What this standard covers

This standard specifies the miniature magnetic field probe with a non-contact current measurement methods to measure the integrated circuit (IC) pin of RF current approach. This method can be 150kHz ~ 1GHz frequency range measured RF current generated by the IC. This standard applies to the measurement of a single IC or for the standard test board IC chipset described and compared.

Document data

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